

April 2014

FDMB3800N Dual N-Channel PowerTrench[®] MOSFET 30V, 4.8A, 40mΩ

Features

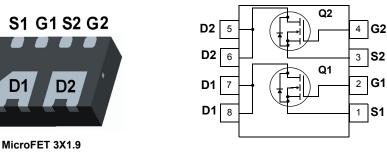
- Max $r_{DS(on)}$ = 40m Ω at V_{GS} = 10V, I_D = 4.8A
- Max $r_{DS(on)}$ = 51m Ω at V_{GS} = 4.5V, I_D = 4.3A
- Fast switching speed
- Low gate Charge
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability.
- RoHS Compliant



General Description

These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.



MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter				Ratings	Units
V _{DS}	Drain to Source Voltage				30	V
V _{GS}	Gate to Source Voltage				±20	V
	Drain Current	-Continuous	T _A = 25°C	(Note 1a)	4.8	^
D	-Pulsed				9	— A
D	Power Dissipation		T _A = 25°C	Note 1a)	1.6	W
P _D	Power Dissipation $T_A = 25^{\circ}C$			(Note 1b)	0.75	V
T _J , T _{STG}	Operating and Storage Junction Temperature Range				-55 to +150	°C

Thermal Characteristics

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	80	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	165	C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
3800	FDMB3800N	MicroFET3X1.9	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	octeristics					
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	30			V
ΔBV _{DSS} ΔTJ	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24V,$ $V_{GS} = 0V$ $T_{J} = 55^{\circ}C$			1 10	μA
GSS	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
	cteristics			-	1	1
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1	1.9	3	V
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage		•	-	Ū	
ΔT_J	Temperature Coefficient	$I_D = 250 \mu A$, referenced to $25^{\circ}C$		-4		mV/°C
r _{DS(on)} Drain		V _{GS} = 10V, I _D = 4.8A		32	40	
	Drain to Source On Resistance	V_{GS} = 4.5V, I_{D} = 4.3A		41	51	mΩ
		V _{GS} = 10V, I _D = 4.8A, T _J = 125°C		43	61	
9 _{FS}	Forward Transconductance	$V_{DS} = 5V, I_{D} = 4.8A$		14		S
Dvnamic	Characteristics					
C _{iss}	Input Capacitance			350	465	pF
C _{oss}	Output Capacitance	$-V_{\rm DS}$ =15V, $V_{\rm GS}$ = 0V,		90	120	pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		40	60	pF
R _g	Gate Resistance	f = 1MHz		3		Ω
d(on)	Turn-On Delay Time	V _{DD} = 15V, I _D = 1A		8 5	16 10	ns ns
t _r	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 6\Omega$		21	34	ns
t _{d(off)} t _f	Fall Time			2	10	ns
Q _{g(TOT)}	Total Gate Charge at 5V	$V_{00} = 0V t_0 5V v_1 - 45V$		4	5.6	nC
≪g(101)	Gate to Source Gate Charge	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 15V$ $I_D = 7.5A$		1.0	0.0	nC
0				1.0		110
				15		nC
Q _{gs} Q _{gd} Drain Sou	Gate to Drain "Miller" Charge			1.5		nC
Q _{gd} Drain-Sou	Gate to Drain "Miller" Charge			1.5	1.25	
Q _{gd} Drain-Sou	Gate to Drain "Miller" Charge urce Diode Characteristics Maximum Continuous Drain - Source Diod	e Forward Current			1.25	A
Q _{gd} Drain-Sou I _S V _{SD}	Gate to Drain "Miller" Charge urce Diode Characteristics Maximum Continuous Drain - Source Diode Source to Drain Diode Forward Voltage			0.8	1.25 1.2	AV
Q _{gd}	Gate to Drain "Miller" Charge urce Diode Characteristics Maximum Continuous Drain - Source Diod	e Forward Current				A

2: Pulse Test: Pulse Width < 300μ s, Duty cycle < 2.0%.

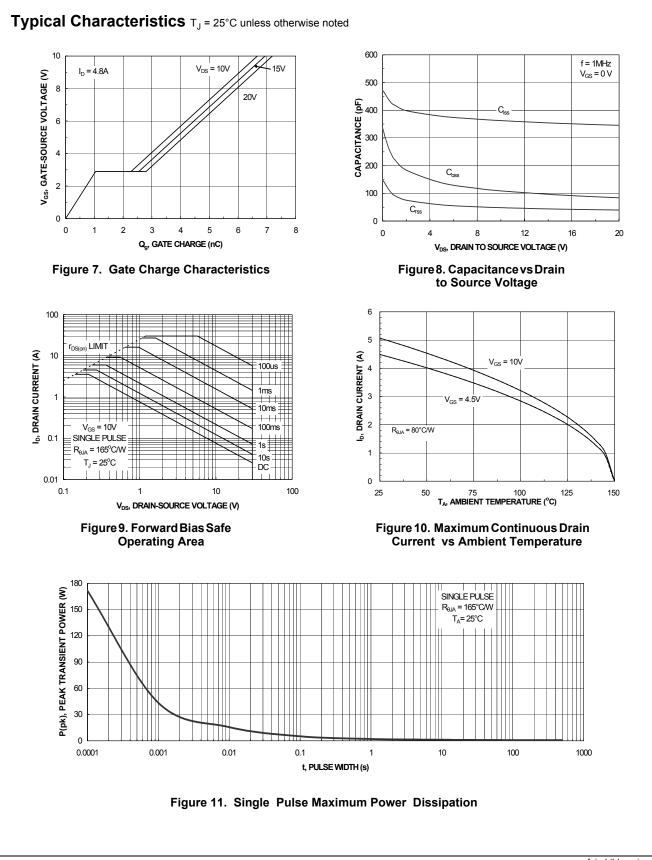
Typical Characteristics T_J = 25°C unless otherwise noted 10 2.8 V_{GS} = 10V 4.5V 3.5V 6.0V 8 V_{GS} = 3.0V 6 3.0V 3.5V 4 4.0V 6.0V 45V2 2.5V 10V 0.8 0 2 8 10 0 0.25 0.5 0.75 1 1.25 0 4 6 V_{DS}, DRAIN-SOURCE VOLTAGE (V) ID, DRAIN CURRENT (A) Figure 1. On Region Characteristics Figure 2. Normalized On - Resistance vs Drain Current and Gate Voltage 0.102 1.6 I_D = 4.8A I_D = 2.4A (WHO) 0.092 NORMALIZED DRAIN-SOURCE ON-RESISTANCE 80 1 7 7 8 V_{GS} = 10V 0.082 0.082 0.072 0.062 T_. = 125°C DRAIN TO SOURCE 0.052 0.042 T_J = 25°C 0.032 0.6 0.022 -50 -25 0 25 50 75 100 125 150 7 2 3 4 5 6 8 9 10 T., JUNCTION TEMPERATURE (°C) V_{GS}, GATE TO SOURCE VOLTAGE (V) Figure 3. Normalized On - Resistance Figure 4. On-Resistance vs Gate to vs Junction Temperature Source Voltage 15 10 Т_J = -55°С ~ 25℃ $V_{DS} = 5V$ V_{GS} = 0V Is, REVERSE DRAIN CURRENT (A) . 125⁰C 1 T_I = 125°C 0.1 25°C 0.01 55°C 0.001 3 0.0001 0 0 0.2 0.4 0.6 0.8 1.2 1 1.5 2 2.5 3 3.5 4 V_{SD}, BODY DIODE FORWARD VOLTAGE (V) V_{GS}, GATE TO SOURCE VOLTAGE (V) Figure 5. Transfer Characteristics Figure 6. Source to Drain Diode Forward Voltage vs Source Current

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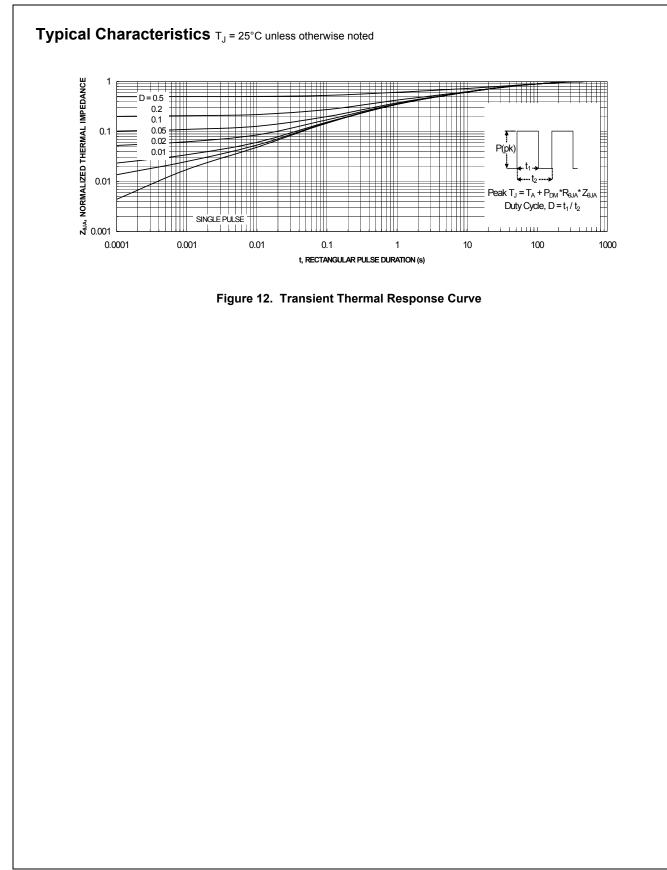
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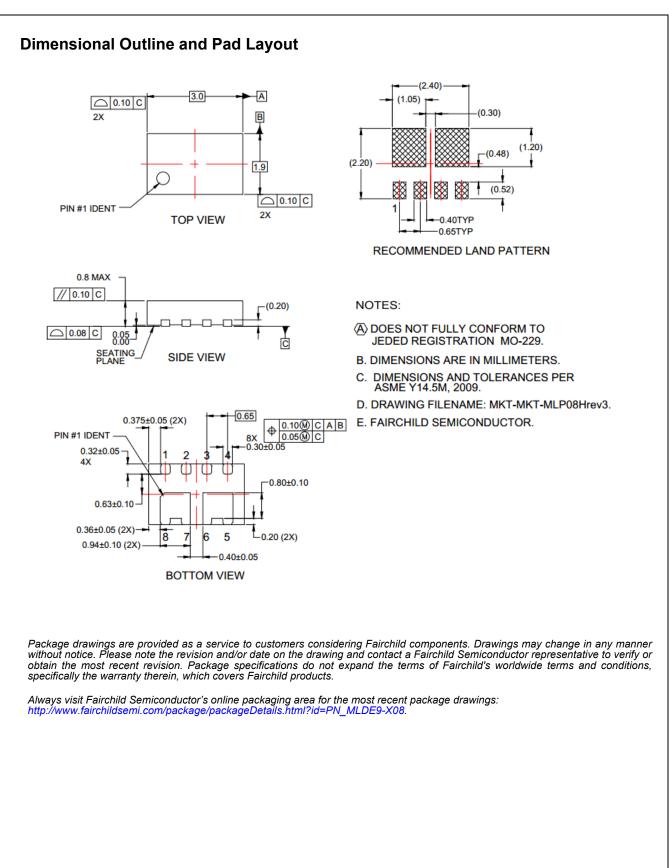
I_b, DRAIN CURRENT (A)

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